

Notice of References Cited	Application/Control No. 10/681,164		Applicant(s)/Patent Under Reexamination SHIEH ET AL.	
	Examiner Vineeta S. Panwalkar		Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0013926 A1	01-2002	Kim et al.	714/781
*	B	US-2002/0041640 A1	04-2002	Le Bars et al.	375/340
*	C	US-2002/0090024 A1	07-2002	Tan, Keng Tiong	375/146
*	D	US-6,490,461 B1	12-2002	Muller, Walter	455/522
*	E	US-2003/0063681 A1	04-2003	Olivier, Jan C.	375/265
*	F	US-2004/0264454 A1	12-2004	Rajkumar et al.	370/389
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.